## Application/Control No. Applicant(s)/Patent Under Reexamination 10/829,571 CHEN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2135 Suman Debnath **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2003/0112972! 06-2003 Hattick et al. 380/46 Α US-В US-С UŚ-D US-Ε US-F US-G US-Н US-US-US-Κ US-US-M FOREIGN PATENT DOCUMENTS

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